
Lasers and laser-related equipment — Test method for angle resolved scattering

*Lasers et équipements associés aux lasers — Méthodes d'essai pour
déterminer la dispersion avec résolution angulaire*

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Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Symbols and abbreviated terms	2
5 Scattering geometry	2
6 Test method	3
6.1 Principle.....	3
6.2 Measurement arrangement and test equipment.....	3
6.2.1 General.....	3
6.2.2 Environmental conditions.....	4
6.2.3 Radiation source.....	4
6.2.4 Beam preparation system.....	5
6.2.5 Goniometer.....	5
6.2.6 Detection system.....	6
6.2.7 Specimen preparation.....	6
7 Procedure	7
7.1 General.....	7
7.2 Alignment procedure.....	7
7.2.1 General.....	7
7.2.2 Alignment of the instrument.....	7
7.2.3 Alignment of the specimen.....	8
7.3 Calibration.....	8
7.3.1 General.....	8
7.3.2 Method 1.....	8
7.3.3 Method 2.....	9
7.4 Measurement procedure.....	9
7.4.1 Selection of specimen position.....	10
7.4.2 Selection of illumination conditions.....	11
7.4.3 Selection of angular scan range.....	11
7.4.4 Determination of the ARS.....	11
7.5 Uncertainty considerations.....	11
8 Measurement protocol	12
Bibliography	14

Foreword

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